

<b>Notice of References Cited</b>	Application/Control No. 10/577,105		Applicant(s)/Patent Under Reexamination KLEIN GUNNEWIEK ET AL.	
	Examiner HEE-YONG KIM		Art Unit 2621	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,398,068 A	03-1995	Liu et al.	375/240.16
*	B	US-5,619,268 A	04-1997	Kobayashi et al.	375/240.15
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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